



Features

- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology
- ★ 100% EAS Guaranteed

Product Summary

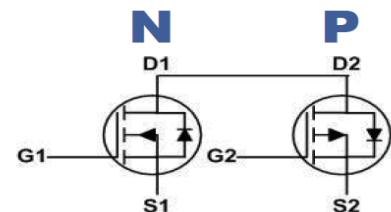
RoHS

BVDSS	RDS(ON)	ID
30V	15mΩ	20A
-30V	25mΩ	-23A

Description

The 3020 is th high performance complementary N-ch and P-ch MOSFETs with high cell density, which provide excellent RDS(ON) and gate charge for most of the synchronous buck converter applications. The 3020 meet the RoHS and Green Product requirement 100% EAS guaranteed with full function reliability approved.

TO252-4 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating		Units
		N-Ch	N-Ch	
V _{DS}	Drain-Source Voltage	30	-30	V
V _{GS}	Gate-Source Voltage	±20	±20	V
I _D @T _c =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	20	-23	A
I _D @T _c =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	15	-14	A
I _{DM}	Pulsed Drain Current ²	60	-60	A
EAS	Single Pulse Avalanche Energy ³	26.6	38	mJ
P _D @T _c =25°C	Total Power Dissipation ⁴	20.8	20.8	W
P _D @T _A =25°C	Total Power Dissipation ⁴	2	2	W
T _{STG}	Storage Temperature Range	-55 to 150	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-Ambient ₁	---	62	°C/W
R _{θJC}	Thermal Resistance Junction-Case ₁	---	6	°C/W

N-Channel Electrical Characteristics $T_J=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$	30	---	---	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	BV_{DSS} Temperature Coefficient	Reference to 25°C , $I_D=1\text{mA}$	---	0.023	---	$^\circ\text{C}$
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_D=10\text{A}$	---	15	20	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_D=6\text{A}$	---	20	25	
$V_{\text{GS(th)}}$	Gate Threshold Voltage		1	---	2.5	V
$\Delta V_{\text{GS(th)}}$	$V_{\text{GS(th)}}$ Temperature Coefficient	$V_{\text{GS}}=V_{\text{DS}}$, $I_D=250\mu\text{A}$	---	-4.2	---	$\text{mV}/^\circ\text{C}$
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=24\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=25^\circ\text{C}$	---	---	1	uA
		$V_{\text{DS}}=24\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=55^\circ\text{C}$	---	---	5	
I_{GSS}	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}$, $I_D=10\text{A}$	---	14	---	S
R_g	Gate Resistance	$V_{\text{DS}}=0\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	2.3	---	Ω
Q_g	Total Gate Charge (4.5V)		---	5	---	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=20\text{V}$, $V_{\text{GS}}=4.5\text{V}$, $I_D=10\text{A}$	---	1.11	---	
Q_{gd}	Gate-Drain Charge		---	2.61	---	
$T_{\text{d(on)}}$	Turn-On Delay Time		---	7.7	---	ns
T_r	Rise Time	$V_{\text{DD}}=12\text{V}$, $V_{\text{GS}}=10\text{V}$, $R_G=3.3\Omega$ $I_D=6\text{A}$	---	46	---	
$T_{\text{d(off)}}$	Turn-Off Delay Time		---	11	---	
T_f	Fall Time		---	3.6	---	
C_{iss}	Input Capacitance	$V_{\text{DS}}=15\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	416	---	pF
C_{oss}	Output Capacitance		---	62	---	
C_{rss}	Reverse Transfer Capacitance		---	51	---	

Diode Characteristics

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units
I_s	Continuous Source Current ^{1,5}	$V_G=V_D=0\text{V}$, Force Current	---	---	20	A
I_{SM}	Pulsed Source Current ^{2,5}		---	---	40	A
V_{SD}	Diode Forward Voltage ²	$V_{\text{GS}}=0\text{V}$, $I_s=1\text{A}$, $T_J=25^\circ\text{C}$	---	---	1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=25\text{V}$, $V_{\text{GS}}=10\text{V}$, $L=0.1\text{mH}$, $I_{\text{AS}}=20\text{A}$
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

P-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=-250\mu\text{A}$	-30	---	---	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	BV_{DSS} Temperature Coefficient	Reference to 25°C , $I_{\text{D}}=-1\text{mA}$	---	-0.021	---	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ₂	$V_{\text{GS}}=-10\text{V}$, $I_{\text{D}}=-8\text{A}$	---	25	30	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}$, $I_{\text{D}}=-6\text{A}$	---	30	35	
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{GS}}=V_{\text{DS}}$, $I_{\text{D}}=-250\mu\text{A}$	-1	---	-2.5	V
$\Delta V_{\text{GS}(\text{th})}$	$V_{\text{GS}(\text{th})}$ Temperature Coefficient		---	-4.2	---	$\text{mV}/^\circ\text{C}$
I_{DS}	Drain-Source Leakage Current	$V_{\text{DS}}=-24\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=25^\circ\text{C}$	---	---	1	μA
		$V_{\text{DS}}=-24\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=55^\circ\text{C}$	---	---	5	
I_{GS}	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-5\text{V}$, $I_{\text{D}}=-8\text{A}$	---	12.6	---	S
R_g	Gate Resistance	$V_{\text{DS}}=0\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	15	---	Ω
Q_g	Total Gate Charge (-4.5V)	$V_{\text{DS}}=-20\text{V}$, $V_{\text{GS}}=-4.5\text{V}$, $I_{\text{D}}=-6\text{A}$	---	9.8	---	nC
Q_{gs}	Gate-Source Charge		---	2.2	---	
Q_{gd}	Gate-Drain Charge		---	3.4	---	
$T_{\text{d}(\text{on})}$	Turn-On Delay Time	$V_{\text{DD}}=-24\text{V}$, $V_{\text{GS}}=-10\text{V}$, $R_G=3.3\Omega$, $I_{\text{D}}=1\text{A}$	---	16.4	---	ns
T_r	Rise Time		---	20.2	---	
$T_{\text{d}(\text{off})}$	Turn-Off Delay Time		---	55	---	
T_f	Fall Time		---	10	---	
C_{iss}	Input Capacitance	$V_{\text{DS}}=-15\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	930	---	pF
C_{oss}	Output Capacitance		---	148	---	
C_{rss}	Reverse Transfer Capacitance		---	115	---	

Diode Characteristics

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units
I_s	Continuous Source Current _{1,5}	$V_G=V_D=0\text{V}$, Force Current	---	---	-23	A
I_{SM}	Pulsed Source Current _{2,5}		---	---	-35	A
V_{SD}	Diode Forward Voltage ₂	$V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=-1\text{A}$, $T_J=25^\circ\text{C}$	---	---	-1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=-25\text{V}$, $V_{\text{GS}}=-10\text{V}$, $L=0.1\text{mH}$, $I_{\text{AS}}=-30\text{A}$
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I_{D} and I_{DM} , in real applications , should be limited by total power dissipation.

N-Channel Typical Performance Characteristics

Figure 1: Output Characteristics

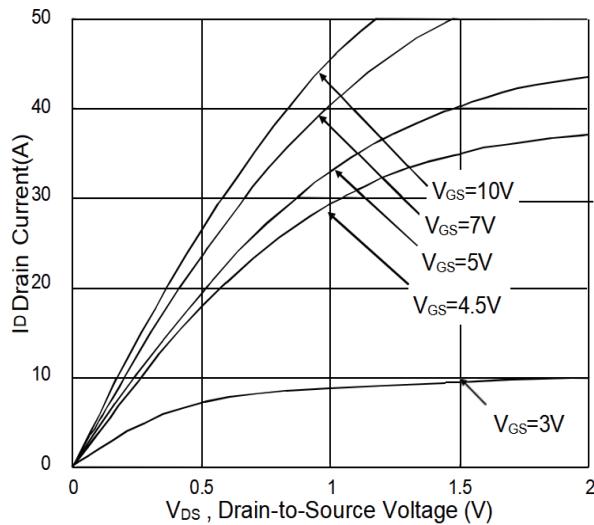


Figure 2: On-Resistance vs. Gate-Source

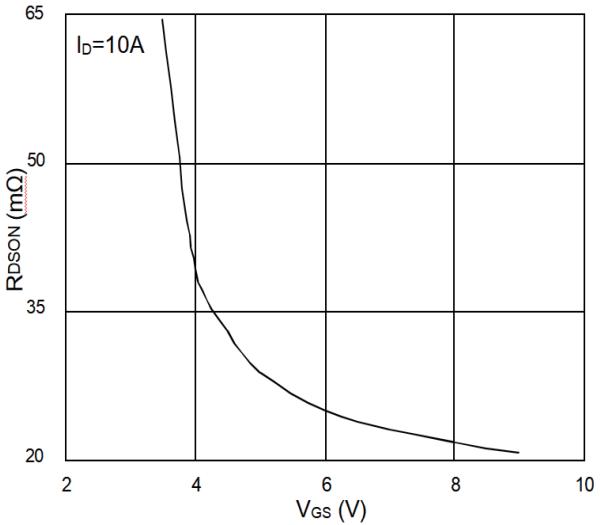


Figure 3: Forward Characteristics Of Reverse

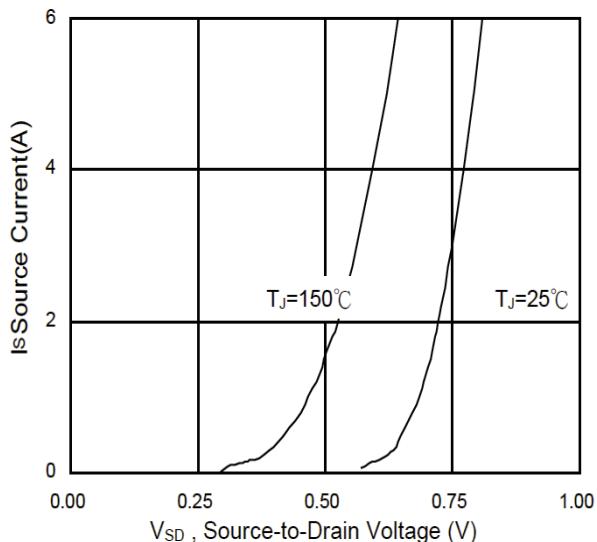
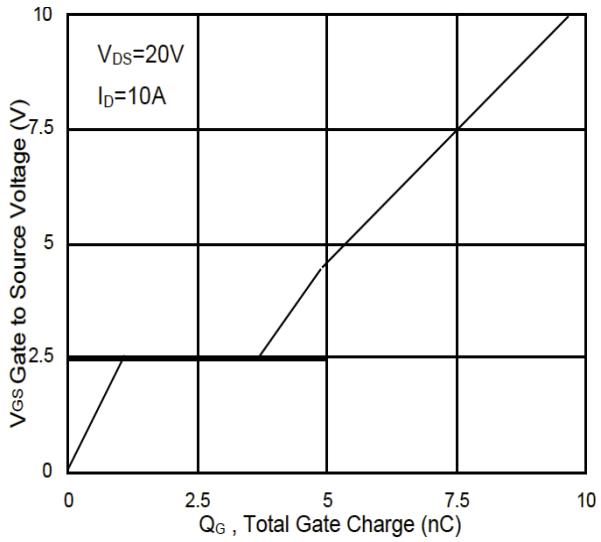
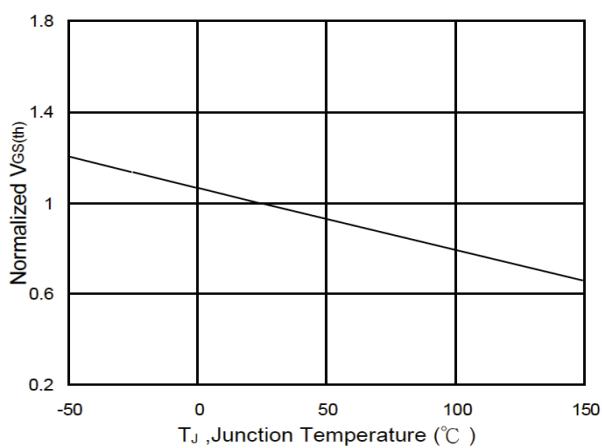
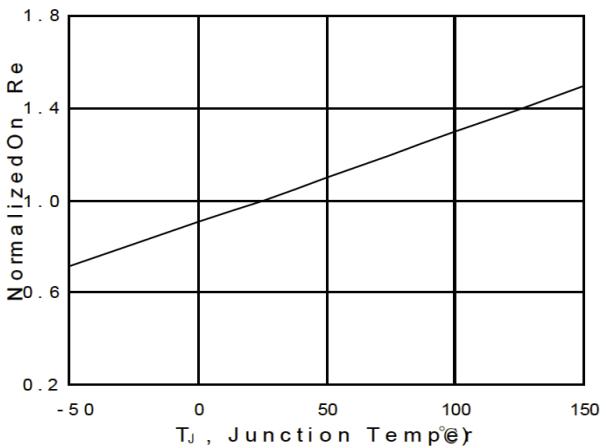


Figure 4: Gate-Charge Characteristics

Figure 5: Normalized $V_{GS(th)}$ vs. T_J Figure 6: Normalized $R_{DS(on)}$ vs. T_J 

N-Channel Typical Performance Characteristics

Figure 7: Capacitance

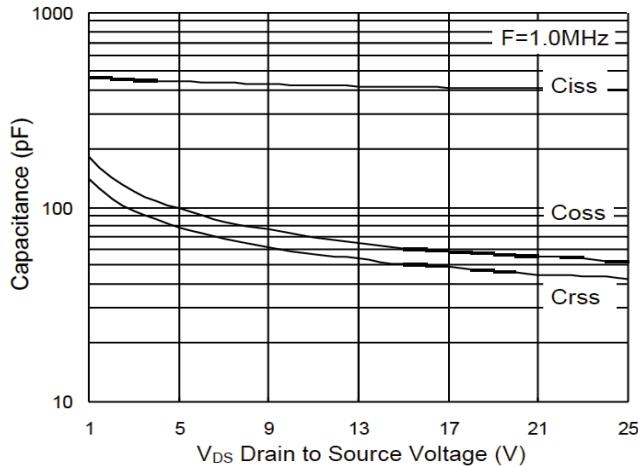


Figure 8 Safe Operating Area

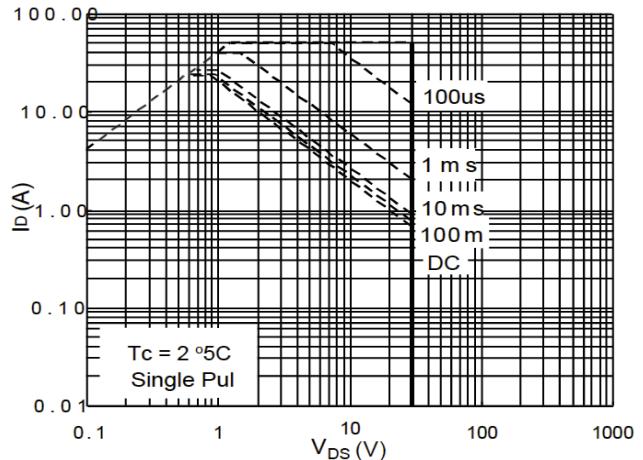


Figure 9: Normalized Maximum Transient Thermal Resistance

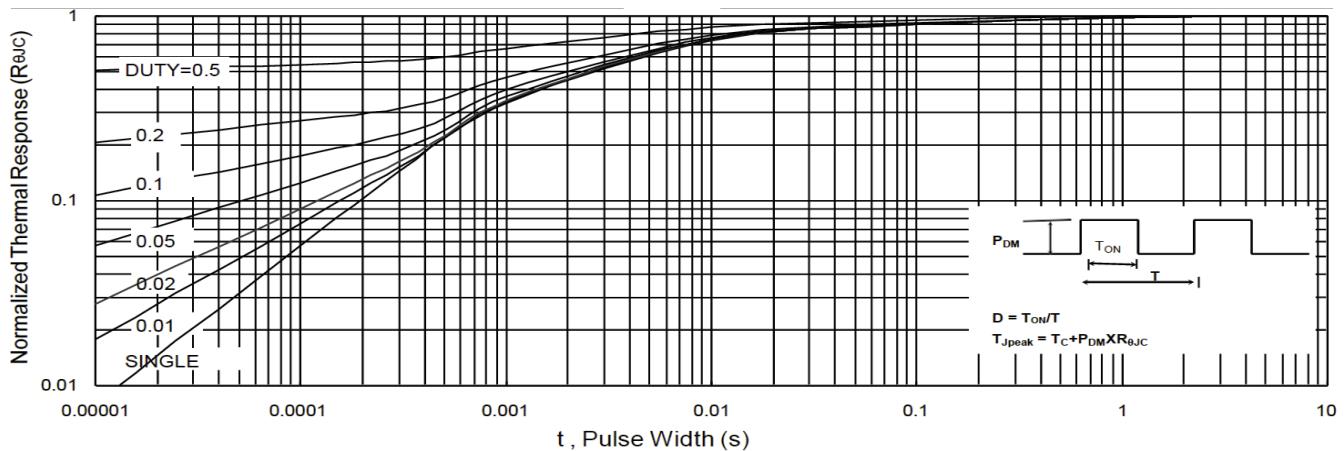


Figure 10: Switching Time Waveform

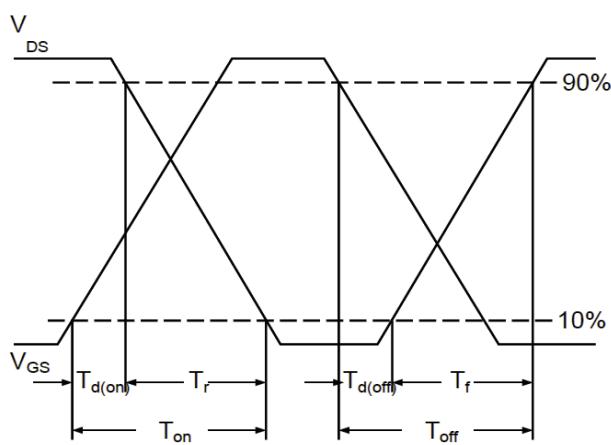
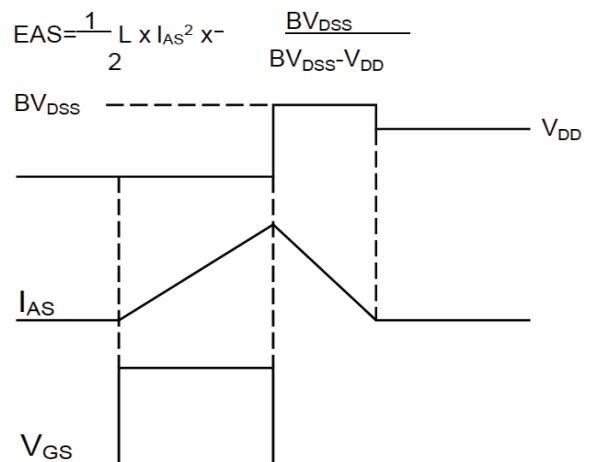


Figure 11: Unclamped Inductive Switching



P-Channel Typical Performance Characteristics

Figure 1: Capacitance

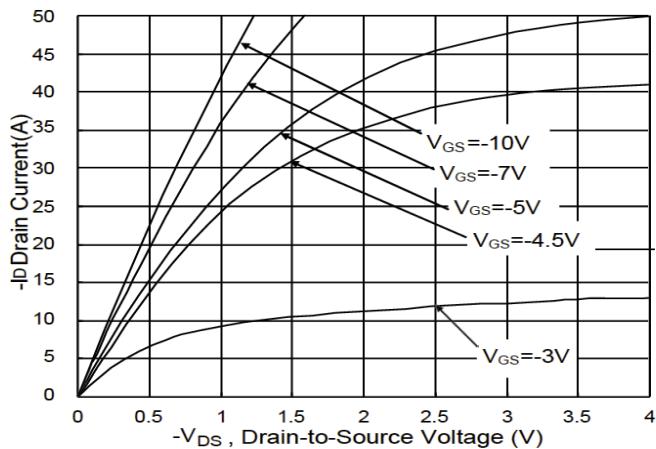


Figure 2: On-Resistance v.s Gate-Source

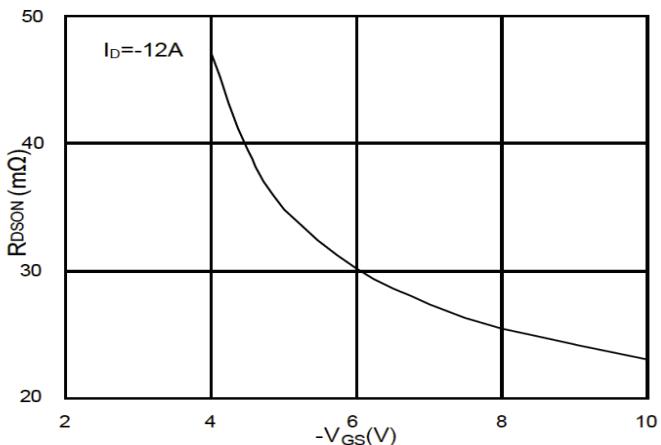


Figure 3: Forward Characteristics Of Reverse

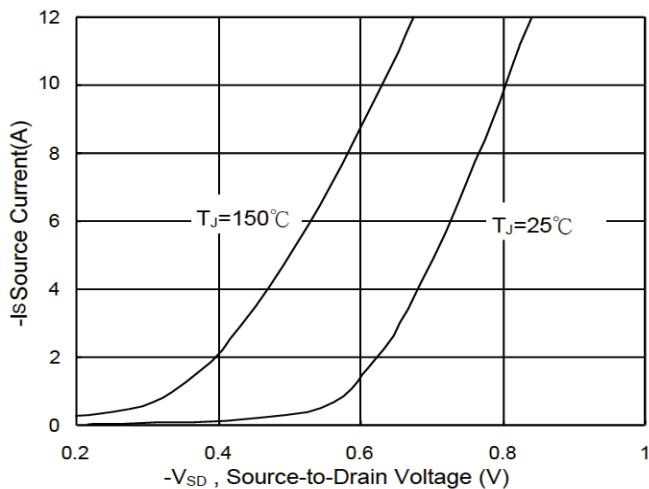


Figure 4: Gate-Charge Characteristics

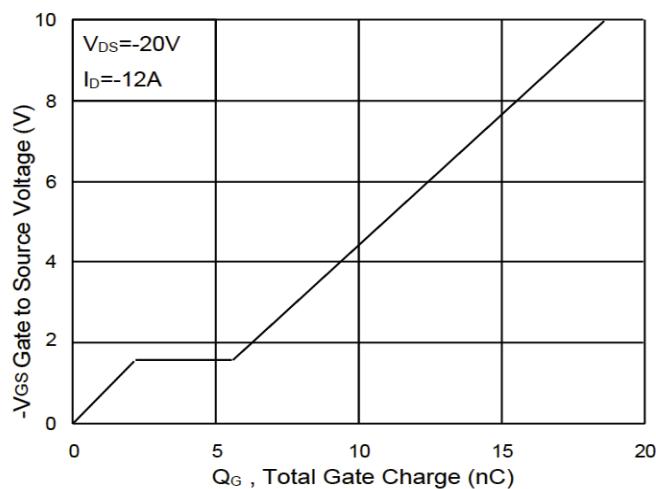


Figure 5: Normalized $V_{GS(th)}$ v.s T_J

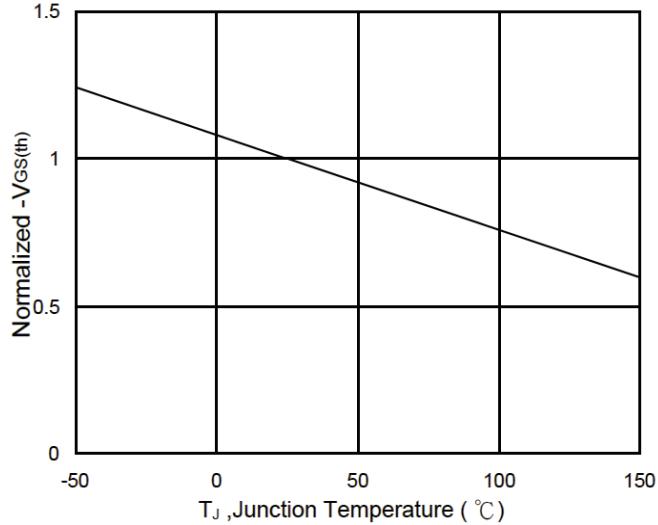
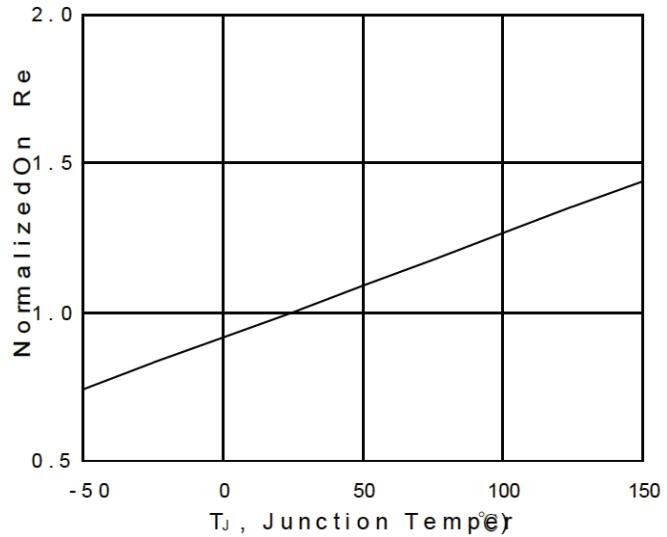


Figure 6: Normalized RDS(on) v.s T_J



P-Channel Typical Performance Characteristics

Figure 7: Capacitance

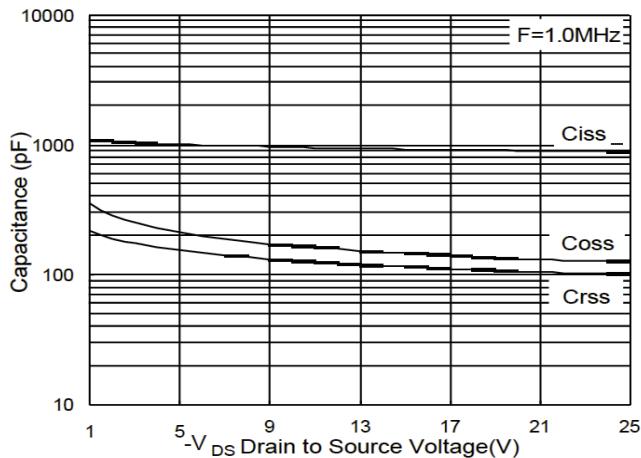


Figure 8: Safe Operating Area

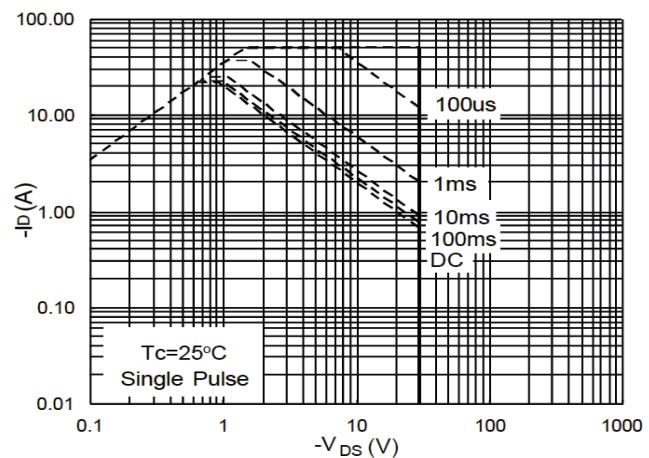


Figure 9: Normalized Maximum Transient

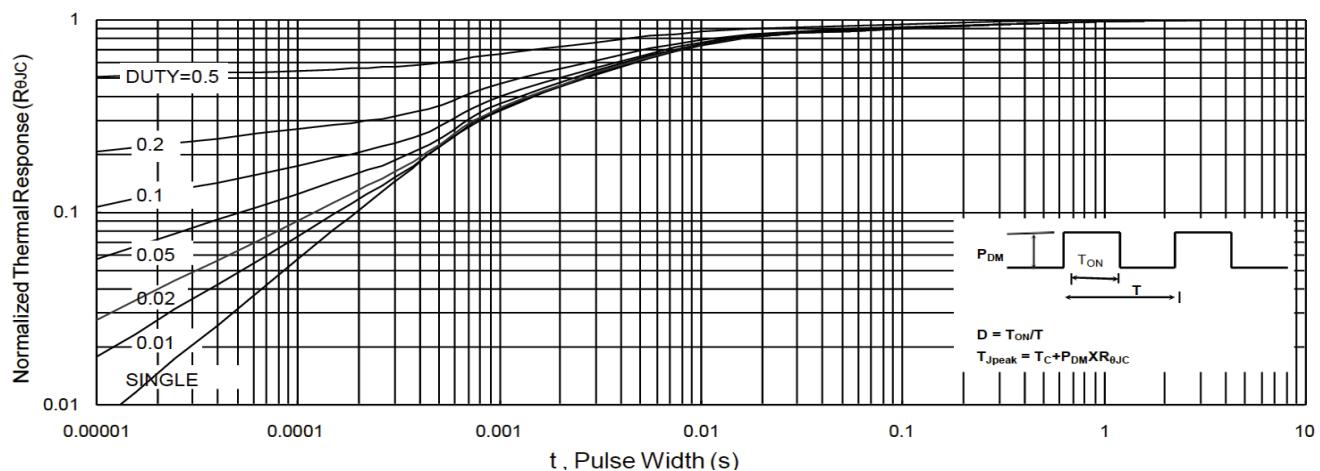


Figure 10: Switching Time Waveforms

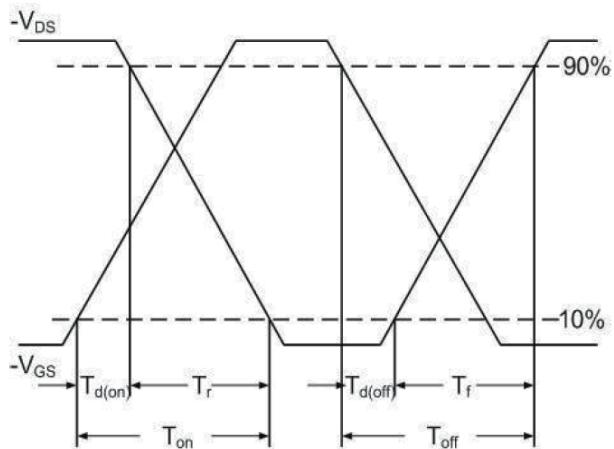
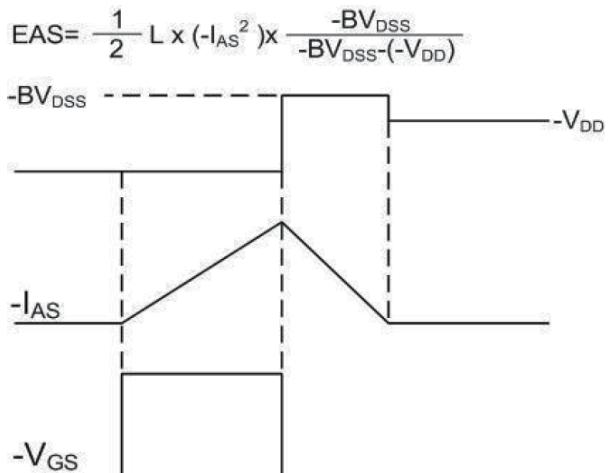
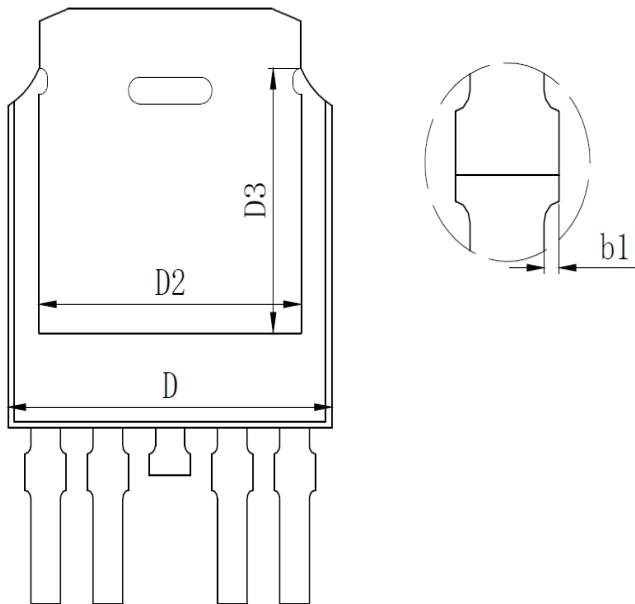
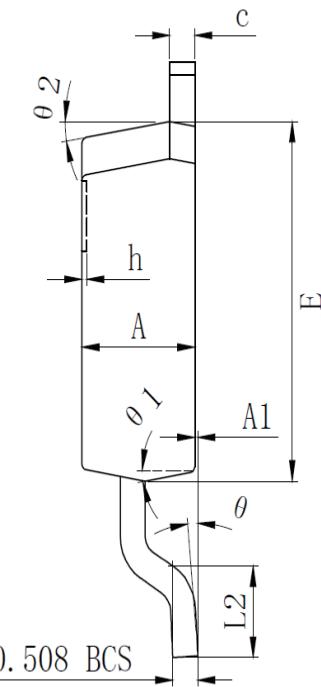
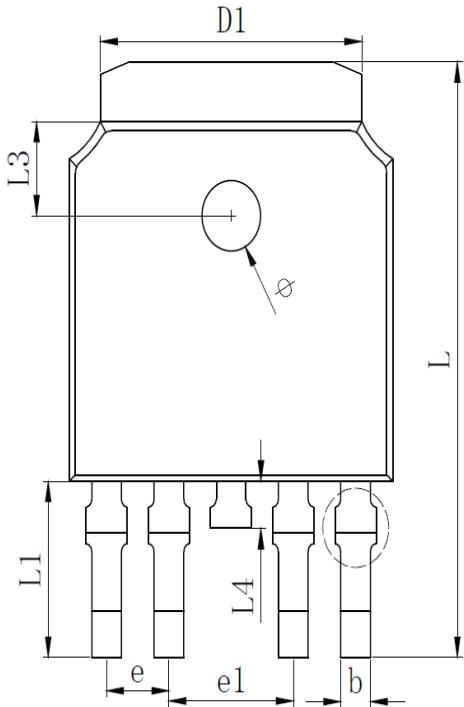


Figure 11: Unclamped Inductive Switching



Mechanical Dimensions for TO-252-4L



SYMBOL	MILLIMETER		
	MIN	Typ.	MAX
A	2.200	2.300	2.400
A1	0.000		0.127
b	0.550	0.600	0.650
b1	0.000		0.120
c(电镀后)	0.460	0.520	0.580
D	6.500	6.600	6.700
D1	5.334	REF	
D2	5.346	REF	
D3	4.490	REF	
E	6.000	6.100	6.200
e		1.270	TYP
e1		2.540	TYP
h	0.000	0.100	0.200
L	9.900	10.100	10.300
L1	2.988	REF	
L2	1.400	1.550	1.700
L3	1.600	REF	
L4	0.700	0.800	0.900
ϕ	1.100	1.200	1.300
θ	0°		8°
θ_1		9°	TYP
θ_2		9°	TYP

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